

<u>AP80P06NF</u>

D

-60V P-Channel Enhancement Mode MOSFET

Description

The AP80P06NF uses advanced trench technology

to provide excellent $R_{\text{DS}(\text{ON})},$ low gate charge and

operation with gate voltages as low as 6V. This

device is suitable for use as a

Battery protection or in other Switching application.

General Features

V_{DS} = -60V I_D =-80A

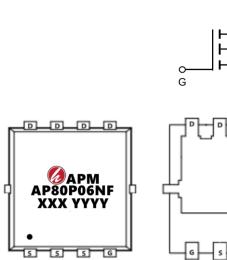
 $R_{DS(ON)} < 11m\Omega @ V_{GS}=-10V (Type: 9m\Omega)$

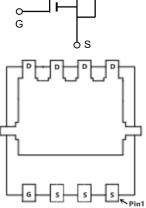
Application

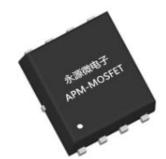
Lithium battery protection

Wireless impact

Mobile phone fast charging









Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)	
AP80P06NF	PDFN5*6-8L	AP80P06NF XXX YYYY	5000	

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Symbol Parameter		Units
Vds	Drain-Source Voltage	-60	V
Vgs	Gate-Source Voltage	±20	V
I₀@Tc=25°C	$I_D@T_c=25^{\circ}C$ Continuous Drain Current, -V _{GS} @ -10V ¹		A
I⊳@Tc=100°C	Continuous Drain Current, -V _{GS} @ -10V ¹	-38	А
Ідм	Pulsed Drain Current ²	-240	A
EAS	Single Pulse Avalanche Energy ³	400	mJ
las	IAS Avalanche Current		A
P _D @T _C =25°C	P _D @T _C =25°C Total Power Dissipation ⁴		W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Reja	R _{0JA} Thermal Resistance Junction-Ambient ¹		°C/W
Rejc Thermal Resistance Junction-Case ¹		70	°C/W



-60V P-Channel Enhancement Mode MOSFET

Electrical Characteristics (Tc=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-60	-68		V	
$\triangle BVDSS / \triangle TJ$	BV _{DSS} Temperature Coefficient	Reference to 25° C , I _D =-1mA		-0.035		V/℃	
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-20A		9.0	11	mΩ	
NDS(ON)	Static Drain-Source On-Resistance	V _{GS} =-4.5V , I _D =-15A		12	16	11152	
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.2	-1.8	-2.5	V	
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	VGS-VDS, 1D2000A		4.28		mV/℃	
IDSS	Drain Source Lookage Current	$V_{\text{DS}}\text{=-}60V$, $V_{\text{GS}}\text{=}0V$, $T_{\text{J}}\text{=}25^\circ\!\mathbb{C}$			1		
1033	SS Drain-Source Leakage Current V _{DS} =-60V, V _{GS} =0V,				5	uA	
IGSS	Gate-Source Leakage Current	V_{GS} =±20V , V_{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-20A		50		S	
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.0		Ω	
Qg	Total Gate Charge (-4.5V)			56		nC	
Qgs	Gate-Source Charge	V _{DS} =-30V , V _{GS} =-10V , I _D =- 20A		11			
Q _{gd}	Gate-Drain Charge	2011		9			
Td(on)	Turn-On Delay Time			4.5		ns	
Tr	Rise Time	V _{DD} =-30V , V _{GS} =-10V , R _G =3Ω,		2.5			
Td(off)	Turn-Off Delay Time	I _D =-20A		14.5			
T _f	Fall Time			3.8			
Ciss	Input Capacitance			3500			
Coss	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		600		pF	
Crss	Reverse Transfer Capacitance			25			
ls	Continuous Source Current ^{1,5}				-80	А	
ISM	Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			-240	А	
VSD	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , TJ=25℃			-1.2	V	

Note :

 $1_{\mbox{\tiny V}}$ The data tested by surface mounted on a 1 inch 2 $\,$ FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width $\leq\,300\text{us}$, duty cycle $\leq\,2\%$

3、The EAS data shows Max. rating . The test condition is VDD =-48V,VGS =-10V,L=0.1mH,IAS =-41A

 $4\,{\scriptstyle \sim}\,$ The power dissipation is limited by 150 $^\circ\!{\rm C}$ junction temperature

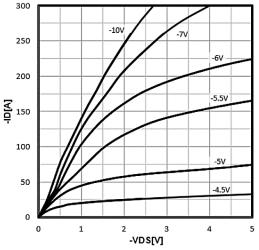
5. The data is theoretically the same as I D and I DM, in real applications, should be limited by total power dissipation.

N

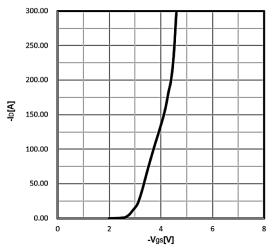


-60V P-Channel Enhancement Mode MOSFET

Typical Characteristics









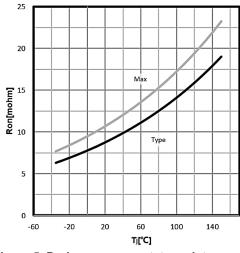


Figure 5. Drain-source on-state resistance RDS(on) =f(Tj); ID =80A; VGS =10V

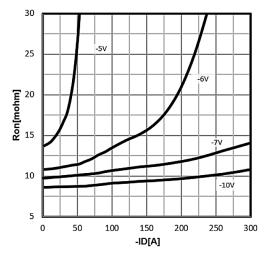
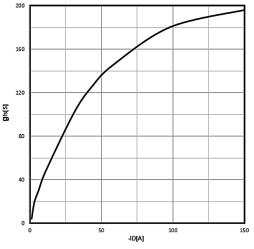


Figure 2. Type. drain-source on resistance



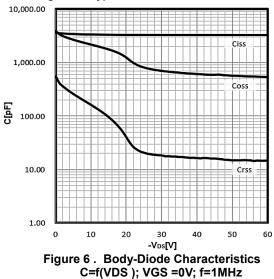


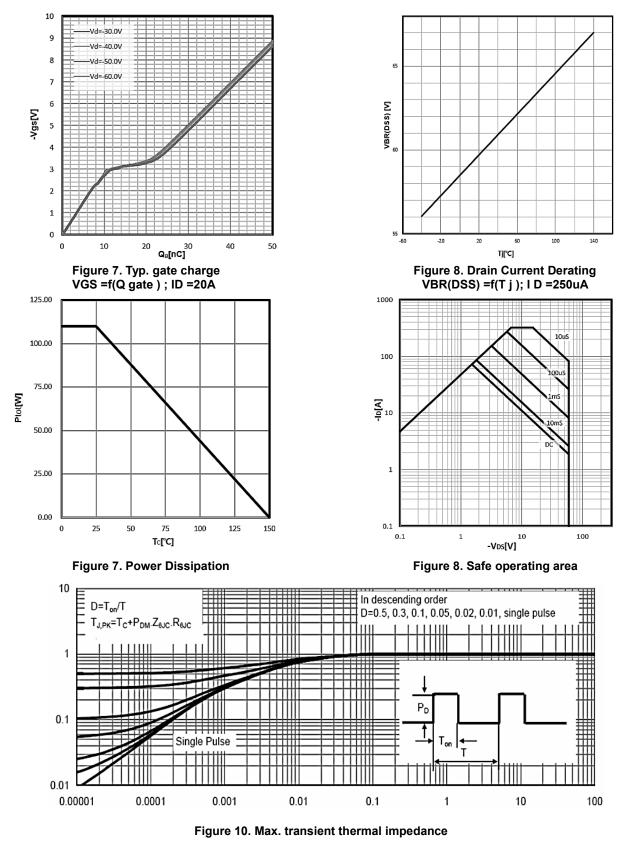
Figure 4. Type. forward transconductance

ω



<u>AP80P06NF</u>

-60V P-Channel Enhancement Mode MOSFET

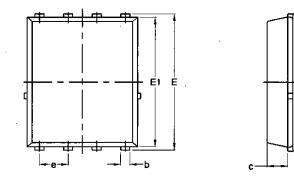


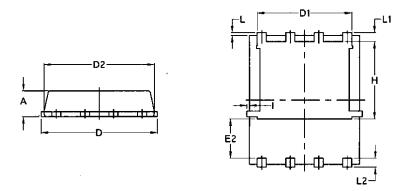




-60V P-Channel Enhancement Mode MOSFET

Package Mechanical Data-DFN5*6-8L-JQ Single





	Common				
Symbol	mm		Inch		
	Mim	Max	Min	Max	
А	1.03	1.17	0.0406	0.0461	
b	0.34	0.48	0.0134	0.0189	
С	0.824	0.0970	0.0324	0.082	
D	4.80	5.40	0.1890	0.2126	
D1	4.11	4.31	0.1618	0.1697	
D2	4.80	5.00	0.1890	0.1969	
E	5.95	6.15	0.2343	0.2421	
E1	5.65	5.85	0.2224	0.2303	
E2	1.60	/	0.0630	/	
е	1.27 BSC		0.05	BSC	
L	0.05	0.25	0.0020	0.0098	
L1	0.38	0.50	0.0150	0.0197	
L2	0.38	0.50	0.0150	0.0197	
Н	3.30	3.50	0.1299	0.1378	
	/	0.18	/	0.0070	



-60V P-Channel Enhancement Mode MOSFET

Attention

1, Any and all APM Microelectronics products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your APM Microelectronics representative nearest you before using any APM Microelectronics products described or contained herein in such applications.

2,APM Microelectronics assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all APM Microelectronics products described or contained herein.

3, Specifications of any and all APM Microelectronics products described or contained here instipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

4, APM Microelectronics Semiconductor CO., LTD. strives to supply high quality high reliabilityproducts. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. Whendesigning equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.

5, In the event that any or all APM Microelectronics products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.

6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of APM Microelectronics Semiconductor CO., LTD.

7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. APM Microelectronics believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.

8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement,etc. When designing equipment, refer to the "DeliverySpecification" for the APM Microelectronics product that you Intend to use.

ວ



-60V P-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2020/1/16	Initial release

Copyright Attribution"APM-Microelectronice"